## Issue Classification

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	Application/Control No.	Applicant(s)/Patent Under Reexamination						
7	09900584	NAKANO, TAKEHIKO						
	Examiner	Art Unit						
	Cervetti, David G	2136						

ORIGINAL					INTERNATIONAL CLASSIFICATION										
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		<u> </u>	NASSER MOAZZAMI												
Cervetti, David Garcia 10/04/2007		1							Total Claims Allowed:						
(Assistant Examiner) (Date)				SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100							12				
										O.G.	O.G. Print Claim(s)			O.G. Print Figure	
(Legal Instruments (Date) Examiner)			(Primary	(Primary Examiner) (O/5) 0 =					Date)	1				7	